Erratum to: Low-temperature creep in pure metals and alloys

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This erratum corrects Fig. 3a–c, with 3a–d below. The original figures do not include an important 1-year RT (longest in the literature) creep test at a stress (15 MPa) less than the yield stress at a conventional strain rate 10^{-4} s^{-1} .

The online version of the original article can be found under doi:[10.1007/s10853-015-9219-2](https://doi.org/10.1007/s10853-015-9219-2).

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Figure 3a was never included in the original manuscript. The original strain–time (linear) is now included along with 3a also now including the 1-year copper test.

Figure 3b now includes the 1-year copper test and replaces Fig. a in the original manuscript.

Figure 3c now includes the 1-year copper test and replaces Fig. b in the original manuscript.

Figure 3d with replaced 3c in the manuscript reports the difference in the quality for logarithmic and power law fits with the addition of a 1-year

copper creep test below the conventional yield stress. The quality of fits with strain and stress varies; new low stress at longer times shows PL behavior, and

higher stress at longer times shows log behavior. Lower stress to longer time evinces logarithmic behavior. For shorter times (<1 h) PL and log may equally describe the data.

Also, not included in the original paper are two RT creep silver tests Figs. Xa and Xb, one above and one

below the conventional yield stress (25 MPa) determined at a conventional strain rate of 10^{-4} s^{-1} . RT creep tests on silver are rare. The Ag behavior is inconsistent with the Seeger model discussed in the original manuscript.